

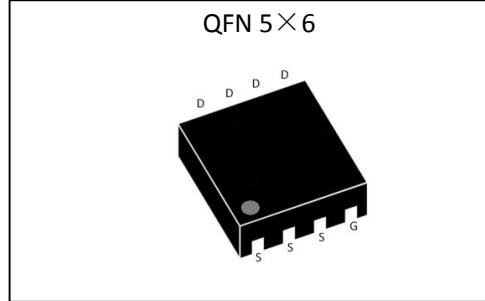
Silicon N-Channel Power MOSFET
General Description :

The HMQ170N03 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications. The package form is QFN 5×6 which accords with the RoHS standard.

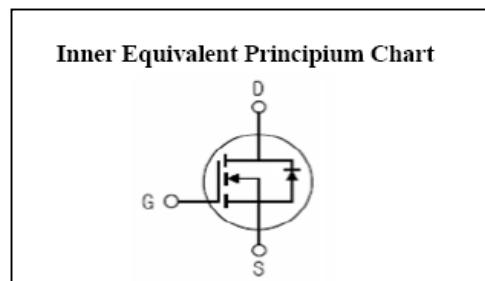
V_{DSS}	30	V
I_D	170	A
P_D	88	W
$R_{DS(ON)}\text{type}$	1.35	$\text{m}\Omega$

Features :

- $R_{DS(ON)} < 1.65\text{m}\Omega$ @ $V_{GS}=10\text{V}$ (Typ1.35mΩ)
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation


Applications :

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply


Absolute ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	30	V
I_D	Continuous Drain Current	170	A
I_{DM}	Pulsed Drain Current	400	A
V_{GS}	Gate-to-Source Voltage	± 20	V
P_D	Power Dissipation	88	W
E_{AS}	Single pulse avalanche energy ^{a5}	890	mJ
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	°C

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current ^{a2} (Body Diode)		--	--	170	A
V_{SD}	Diode Forward Voltage ^{a3}	$I_S=85A, V_{GS}=0V$	--	--	1.2	V

Symbol	Parameter	Typ.	Units
R_{eJC}	Junction-to-Case ^{a2}	1.42	°C/W

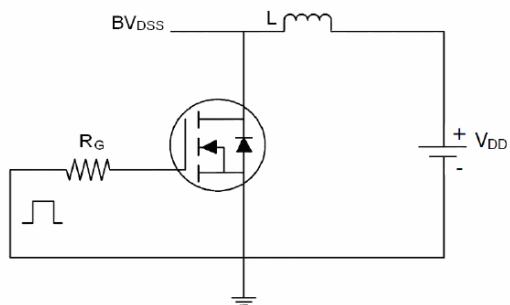
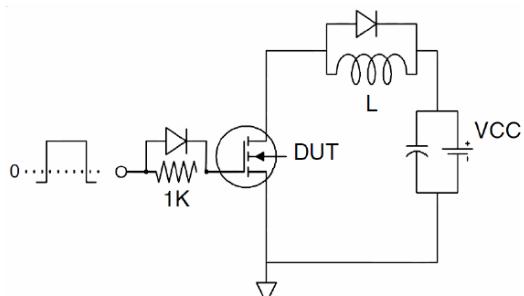
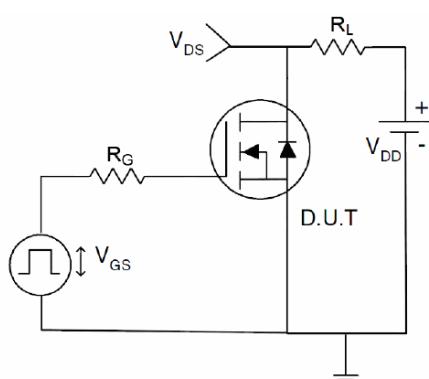
^{a1} : Repetitive Rating: Pulse width limited by maximum junction temperature.

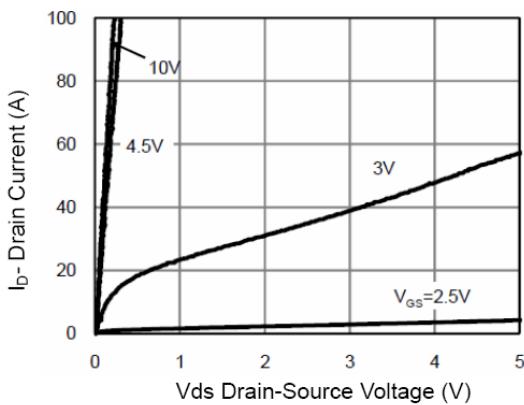
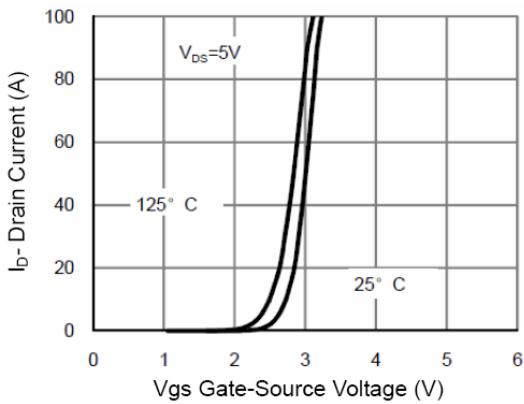
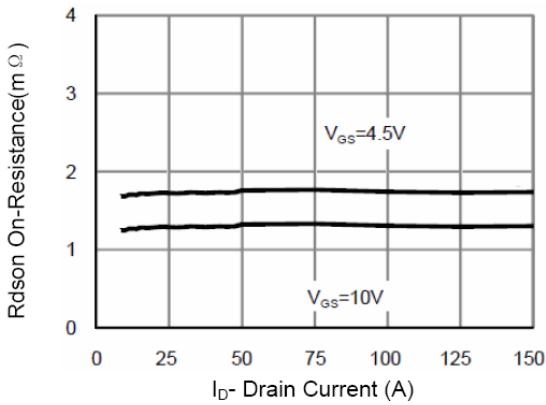
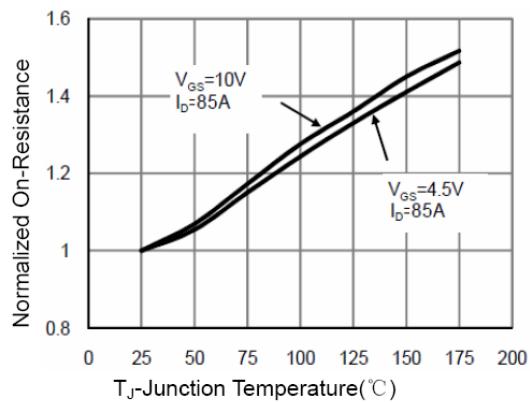
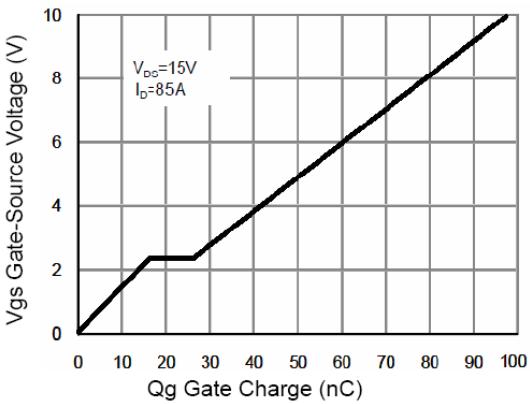
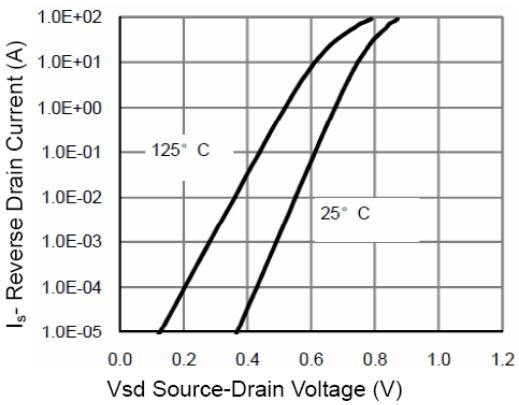
^{a2} : Surface Mounted on FR4 Board, $t \leq 10\text{sec}$.

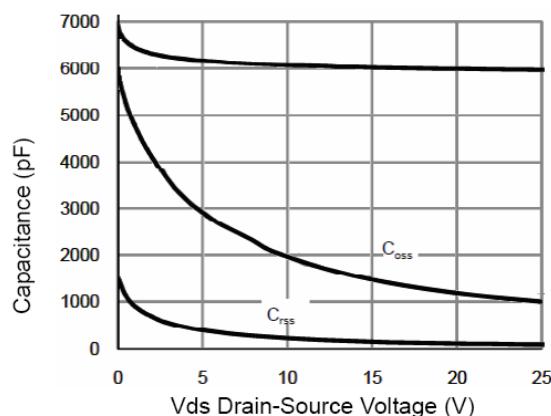
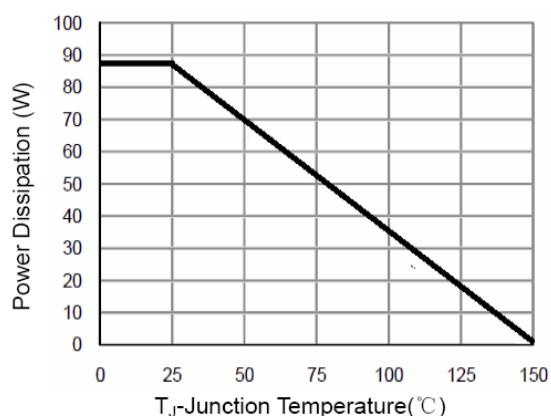
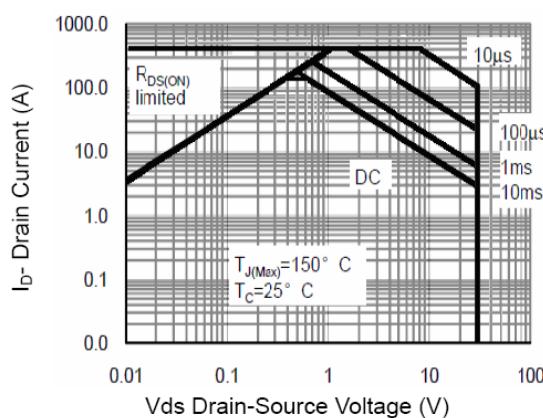
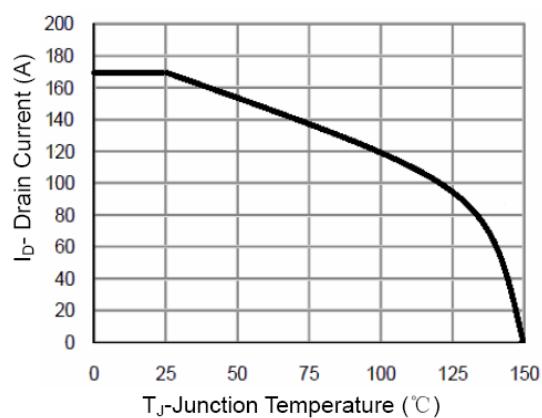
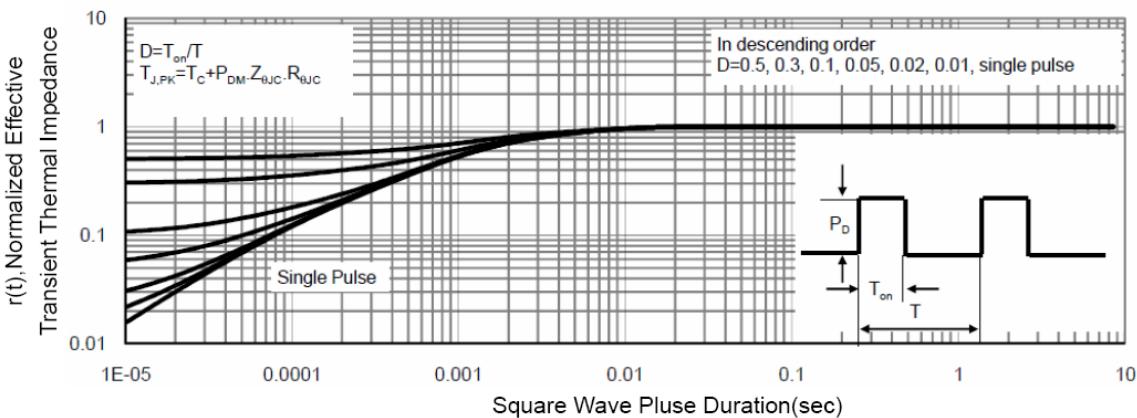
^{a3} : Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

^{a4} : Guaranteed by design, not subject to production

^{a5} : EAS condition : $T_j=25^\circ\text{C}, V_{DD}=20\text{V}, V_G=10\text{V}, L=0.5\text{mH}, R_g=25\Omega$

Test circuit
1) EAS test Circuit

2) Gate charge test Circuit

3) Switch Time Test Circuit


Characteristics Curve :**Figure 1 Output Characteristics****Figure 2 Transfer Characteristics****Figure 3 Rdson- Drain Current****Figure 4 Rdson-Junction Temperature****Figure 5 Gate Charge****Figure 6 Source- Drain Diode Forward**


Figure 7 Capacitance vs Vds

Figure 9 Power De-rating

Figure 8 Safe Operation Area

Figure 10 Current De-rating

Figure 11 Normalized Maximum Transient Thermal Impedance